

**Search Notes**

Application/Control No.

10/625,645

Examiner

Leigh C. Maier

Applicant(s)/Patent under  
Reexamination

CHRISTIAN ET AL.

Art Unit

1623

**SEARCHED**

Class	Subclass	Date	Examiner
536	17.2 22.1 29.1	11/10/2006	LCM
514	25 42	11/10/2006	LCM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
-STN structure search -EAST (transcripts attached)	11/10/2006	LCM